



240pin Unbuffered DDR2 SDRAM MODULE

Based on 64Mx16 DDR2 SDRAM D-die (512MB)

Based on 128Mx8 DDR2 SDRAM D-die (1GB/2GB)

Features

Performance:

	PC2-5300	PC2-6400	PC2-6400	
Speed Sort	-3C	-AD	-AC	Unit
DIMM $\overline{\text{CAS}}$ Latency	5	6	5	
f _{CK} Clock Frequency	333	400	400	MHz
t _{CK} Clock Cycle	3	2.5	2.5	ns
f _{DQ} DQ Burst Frequency	667	800	800	Mbps

- JEDEC Standard 240-pin Dual In-Line Memory Module
- 64Mx64 DDR2 Unbuffered DIMM based on Nanya 64Mx16 DDR2 SDRAM D-die component – (512MB)
- 128Mx64 and 256Mx64 DDR2 Unbuffered DIMM based on Nanya 128Mx8 DDR2 SDRAM D-die component – (1GB/2GB)
- Double Data Rate architecture; two data transfer per clock cycle
- Differential bi-directional data strobe (DQS & $\overline{\text{DQS}}$)
- DQS is edge-aligned with data for reads and is center-aligned with data for writes
- Differential clock inputs (CK & $\overline{\text{CK}}$)
- Intended for 333MHz/400MHz applications
- Inputs and outputs are SSTL-18 compatible
- $V_{DD} = V_{DDQ} = 1.8V \pm 0.1V$
- 7.8 μ s Max. Average Periodic Refresh Interval
- Programmable Operation:
 - Device $\overline{\text{CAS}}$ Latency: 3, 4, 5 (-3C/-AC); 4, 5, 6 (-AD)
 - Burst Length: 4, 8
- Auto Refresh (CBR) and Self Refresh Modes
- Automatic and controlled precharge commands
- 13/10/1 Addressing (row/column/rank) – 512MB
- 14/10/1 Addressing (row/column/rank) – 1GB
- 14/10/2 Addressing (row/column/rank) – 2GB
- Serial Presence Detect
- On Die Termination (ODT)
- OCD impedance adjustment
- Gold contacts
- SDRAMs in 84-ball BGA Package – 512MB
- SDRAMs in 60-ball BGA Package – 1GB/2GB
- RoHs Compliance

Description

NT512T64UH4D0FY, NT1GT64U88D0BY and NT2GT64U8HD0BY are 240-Pin Double Data Rate 2 (DDR2) Synchronous DRAM Unbuffered Dual In-Line Memory Module (UDIMM), organized as one rank 64Mx64 (512MB), one rank 128Mx64 (1GB) and two ranks 256Mx64 (2GB) high-speed memory array. NT512T64UH4D0FY use four 64Mx16 DDR2 SDRAMs, NT1GT64U88D0BY use eight 128Mx8 DDR2 SDRAMs and NT2GT64U8HD0BY use sixteen 128Mx8 DDR2 SDRAMs in BGA packages. These DIMMs are manufactured using raw cards developed for broad industry use as reference designs. The use of these common design files minimizes electrical variation between suppliers. All NANYA DDR2 SDRAM DIMMs provide a high-performance, flexible 8-byte interface in a 5.25” long space-saving footprint.

The DIMM is intended for use in applications operating up to 333MHz (or 400MHz) clock speeds and achieves high-speed data transfer rates of up to 667Mbps (or 800Mbps). Prior to any access operation, the device $\overline{\text{CAS}}$ latency and burst / length /operation type must be programmed into the DIMM by address inputs A0-A12 (512MB) / A0-A13 (1GB/2GB) and I/O inputs BA0, BA1 and BA2 using the mode register set cycle.

The DIMM uses serial presence-detect implemented via a serial 2,048-bit EEPROM using a standard IIC protocol. The first 128 bytes of serial PD data are programmed and locked during module assembly. The remaining 128 bytes are available for use by the customer.

NT512T64UH4D0FY / NT1GT64U88D0BY / NT2GT64U8HD0BY

512MB: 64M x 64 / 1GB: 128M x 64 / 2GB: 256M x 64

Unbuffered DDR2 SDRAM DIMM



Ordering Information

Part Number	Speed			Organization	Leads	Power	Note
NT512T64UH4D0FY-3C	333MHz (3.00ns @ CL = 5)	DDR2-667	PC2-5300	64Mx64	GOLD	1.8V	
NT512T64UH4D0FY-AD	400MHz (2.50ns @ CL = 6)	DDR2-800	PC2-6400				
NT512T64UH4D0FY-AC	400MHz (2.50ns @ CL = 5)	DDR2-800	PC2-6400				
NT1GT64U88D0BY-3C	333MHz (3.00ns @ CL = 5)	DDR2-667	PC2-5300	128Mx64			
NT1GT64U88D0BY-AD	400MHz (2.50ns @ CL = 6)	DDR2-800	PC2-6400				
NT1GT64U88D0BY-AC	400MHz (2.50ns @ CL = 5)	DDR2-800	PC2-6400				
NT2GT64U8HD0BY-3C	333MHz (3.00ns @ CL = 5)	DDR2-667	PC2-5300	256Mx64			
NT2GT64U8HD0BY-AD	400MHz (2.50ns @ CL = 6)	DDR2-800	PC2-6400				
NT2GT64U8HD0BY-AC	400MHz (2.50ns @ CL = 5)	DDR2-800	PC2-6400				

Pin Description

CK0-CK2 $\overline{\text{CK0}}-\overline{\text{CK2}}$	Differential Clock Inputs	DQ0-DQ63	Data input/output
CKE0, CKE1	Clock Enable	DQS0-DQS8	Bidirectional data strobes
$\overline{\text{RAS}}$	Row Address Strobe	DM0-DM8	Input Data Mask
$\overline{\text{CAS}}$	Column Address Strobe	$\overline{\text{DQS0}}-\overline{\text{DQS8}}$	Differential data strobes
$\overline{\text{WE}}$	Write Enable	VDD	Power (1.8V)
$\overline{\text{CS0}}, \overline{\text{CS1}}$	Chip Selects	VREF	Ref. Voltage for SSTL_18 inputs
A0-A9, A0-A12/A13	Address Inputs	VDDSPD	Serial EEPROM positive power supply
A10/AP	Column Address Input/Auto-precharge	VSS	Ground
BA0 ~ BA2	SDRAM Bank Address Inputs	SCL	Serial Presence Detect Clock Input
RESET	Reset pin	SDA	Serial Presence Detect Data input/output
ODT0, ODT1	On-die termination control lines	SA0 ~ SA2	Serial Presence Detect Address Inputs
NC	No Connect		

Note:

1. Address Inputs: 512MB (A0-A9, A0-A12), 1GB/2GB (A0-A9, A0-A13).
2. ODT1, CKE1 and $\overline{\text{CS1}}$ are only support in 2GB module type.

NT512T64UH4D0FY / NT1GT64U88D0BY / NT2GT64U8HD0BY

512MB: 64M x 64 / 1GB: 128M x 64 / 2GB: 256M x 64

Unbuffered DDR2 SDRAM DIMM



Pinout

Pin	Front	Pin	Front	Pin	Front	Pin	Back	Pin	Back	Pin	Back
1	V _{REF}	42	NC	82	V _{SS}	121	V _{SS}	162	NC	202	DM4
2	V _{SS}	43	NC	83	$\overline{\text{DQS4}}$	122	DQ4	163	V _{SS}	203	NC
3	DQ0	44	V _{SS}	84	DQS4	123	DQ5	164	NC	204	V _{SS}
4	DQ1	45	NC^-	85	V _{SS}	124	V _{SS}	165	NC	205	DQ38
5	V _{SS}	46	NC	86	DQ34	125	DM0	166	V _{SS}	206	DQ39
6	$\overline{\text{DQS0}}$	47	V _{SS}	87	DQ35	126	NC	167	NC	207	V _{SS}
7	DQS0	48	NC	88	V _{SS}	127	V _{SS}	168	NC	208	DQ44
8	V _{SS}	49	NC	89	DQ40	128	DQ6	169	V _{SS}	209	DQ45
9	DQ2	50	V _{SS}	90	DQ41	129	DQ7	170	V _{DDQ}	210	V _{SS}
10	DQ3	51	V _{DDQ}	91	V _{SS}	130	V _{SS}	171	NC,CKE1	211	DM5
11	V _{SS}	52	CKE0	92	$\overline{\text{DQS5}}$	131	DQ12	172	V _{DD}	212	NC
12	DQ8	53	V _{DD}	93	DQS5	132	DQ13	173	NC	213	V _{SS}
13	DQ9	54	BA2	94	V _{SS}	133	V _{SS}	174	NC	214	DQ46
14	V _{SS}	55	NC	95	DQ42	134	DM1	175	V _{DDQ}	215	DQ47
15	$\overline{\text{DQS1}}$	56	V _{DDQ}	96	DQ43	135	NC	176	A12	216	V _{SS}
16	DQS1	57	A11	97	V _{SS}	136	V _{SS}	177	A9	217	DQ52
17	V _{SS}	58	A7	98	DQ48	137	CK1	178	V _{DD}	218	DQ53
18	NC	59	V _{DD}	99	DQ49	138	$\overline{\text{CK1}}$	179	A8	219	V _{SS}
19	NC	60	A5	100	V _{SS}	139	V _{SS}	180	A6	220	CK2
20	V _{SS}	61	A4	101	SA2	140	DQ14	181	V _{DDQ}	221	$\overline{\text{CK2}}$
21	DQ10	62	V _{DDQ}	102	NC	141	DQ15	182	A3	222	V _{SS}
22	DQ11	63	A2	103	V _{SS}	142	V _{SS}	183	A1	223	DM6
23	V _{SS}	64	V _{DD}	104	$\overline{\text{DQS6}}$	143	DQ20	184	V _{DD}	224	NC
24	DQ16	KEY		105	DQS6	144	DQ21	KEY		225	V _{SS}
25	DQ17	65	V _{SS}	106	V _{SS}	145	V _{SS}	185	CK0	226	DQ54
26	V _{SS}	66	V _{SS}	107	DQ50	146	DM2	186	$\overline{\text{CK0}}$	227	DQ55
27	$\overline{\text{DQS2}}$	67	V _{DD}	108	DQ51	147	NC	187	V _{DD}	228	V _{SS}
28	DQS2	68	NC	109	V _{SS}	148	V _{SS}	188	A0	229	DQ60
29	V _{SS}	69	V _{DD}	110	DQ56	149	DQ22	189	V _{DD}	230	DQ61
30	DQ18	70	A10/AP	111	DQ57	150	DQ23	190	BA1	231	V _{SS}
31	DQ19	71	BA0	112	V _{SS}	151	V _{SS}	191	V _{DDQ}	232	DM7
32	V _{SS}	72	V _{DDQ}	113	$\overline{\text{DQS7}}$	152	DQ28	192	$\overline{\text{RAS}}$	233	NC
33	DQ24	73	$\overline{\text{WE}}$	114	DQS7	153	DQ29	193	$\overline{\text{CS0}}$	234	V _{SS}
34	DQ25	74	$\overline{\text{CAS}}$	115	V _{SS}	154	V _{SS}	194	V _{DDQ}	235	DQ62
35	V _{SS}	75	V _{DDQ}	116	DQ58	155	DM3	195	ODT0	236	DQ63
36	$\overline{\text{DQS3}}$	76	NC, $\overline{\text{CS1}}$	117	DQ59	156	NC	196	NC,A13	237	V _{SS}
37	DQS3	77	NC,ODT1	118	V _{SS}	157	V _{SS}	197	V _{DD}	238	V _{DDSPD}
38	V _{SS}	78	V _{DDQ}	119	SDA	158	DQ30	198	V _{SS}	239	SA0
39	DQ26	79	V _{SS}	120	SCL	159	DQ31	199	DQ36	240	SA1
40	DQ27	80	DQ32			160	V _{SS}	200	DQ37		
41	V _{SS}	81	DQ33			161	NC	201	V _{SS}		

Note:

1. NC = No Connect.
2. $\overline{\text{CS1}}$, ODT1, CKE1 and A13 (Pins 76, 77, 171 and 196) are only support in 2GB module type.



Input/Output Functional Description

Symbol	Type	Polarity	Function
CK0, CK1, CK2	(SSTL)	Positive Edge	The positive line of the differential pair of system clock inputs which drives the input to the on-DIMM PLL. All the DDR2 SDRAM address and control inputs are sampled on the rising edge of their associated clocks.
$\overline{CK0}$, $\overline{CK1}$, $\overline{CK2}$	(SSTL)	Negative Edge	The negative line of the differential pair of system clock inputs which drives the input to the on-DIMM PLL.
CKE0, CKE1	(SSTL)	Active High	Activates the SDRAM CK signal when high and deactivates the CK signal when low. By deactivating the clocks, CKE low initiates the Power Down mode, or the Self Refresh mode. CKE1 apply on 2GB UDIMM only.
$\overline{CS0}$, $\overline{CS1}$	(SSTL)	Active Low	Enables the associated SDRAM command decoder when low and disables the command decoder when high. When the command decoder is disabled, new commands are ignored but previous operations continue. CS1 apply on 2GB UDIMM only.
\overline{RAS} , \overline{CAS} , \overline{WE}	(SSTL)	Active Low	When sampled at the positive rising edge of the clock, \overline{RAS} , \overline{CAS} , \overline{WE} define the operation to be executed by the SDRAM.
VREF	Supply		Reference voltage for SSTL-18 inputs
VDDQ	Supply		Isolated power supply for the DDR SDRAM output buffers to provide improved noise immunity
ODT0, ODT1	Input	Active High	On-Die Termination control signals. ODT1 apply on 2GB UDIMM only.
BA0 – BA2	(SSTL)	-	Selects which SDRAM bank is to be active.
A0 - A9 A10/AP A11 – A12/A13	(SSTL)	-	During a Bank Activate command cycle, A0-A12/A13 defines the row address (RA0-RA12/RA13) when sampled at the rising clock edge. During a Read or Write command cycle, A0-A9 defines the column address (CA0-CA9) when sampled at the rising clock edge. In addition to the column address, AP is used to invoke "Autoprecharge" operation at the end of the Burst Read or Write cycle. If AP is high, Autoprecharge's selected and BA0/BA1 defines the bank to be precharged. If AP is low, autoprecharge is disabled. During a Precharge command cycle, AP is used in conjunction with BA0/BA1/BA2 to control which bank(s) to precharge. If AP is high all 4 banks will be precharged regardless of the state of BA0/BA1/BA2. If AP is low, then BA0/BA1/BA2 are used to define which bank to pre-charge.
DQ0 – DQ63	(SSTL)	Active High	Data and Check Bit Input / Output pins.
VDD, VSS	Supply		Power and ground for the DDR2 SDRAM input buffers and core logic
DQS0 – DQS8 $\overline{DQS0}$ – $\overline{DQS8}$	(SSTL)	Negative and Positive Edge	Data strobe for input and output data
DM0 – DM8	Input	Active High	The data write masks, associated with one data byte. In Write mode, DM operates as a byte mask by allowing input data to be written if it is low but blocks the write operation if it is high. In Read mode, DM lines have no effect. DM8 is associated with check bits CB0-CB7, and is not used on x64 modules.
SA0 – SA2		-	Address inputs. Connected to either VDD or VSS on the system board to configure the Serial Presence Detect EEPROM address.
SDA		-	This bi-directional pin is used to transfer data into or out of the SPD EEPROM. A resistor must be connected from the SDA bus line to VDD to act as a pull-up.
SCL		-	This signal is used to clock data into and out of the SPD EEPROM. A resistor may be connected from the SCL bus time to VDD to act as a pull-up.
VDDSPD	Supply		Serial EEPROM positive power supply.

NT512T64UH4D0FY / NT1GT64U88D0BY / NT2GT64U8HD0BY

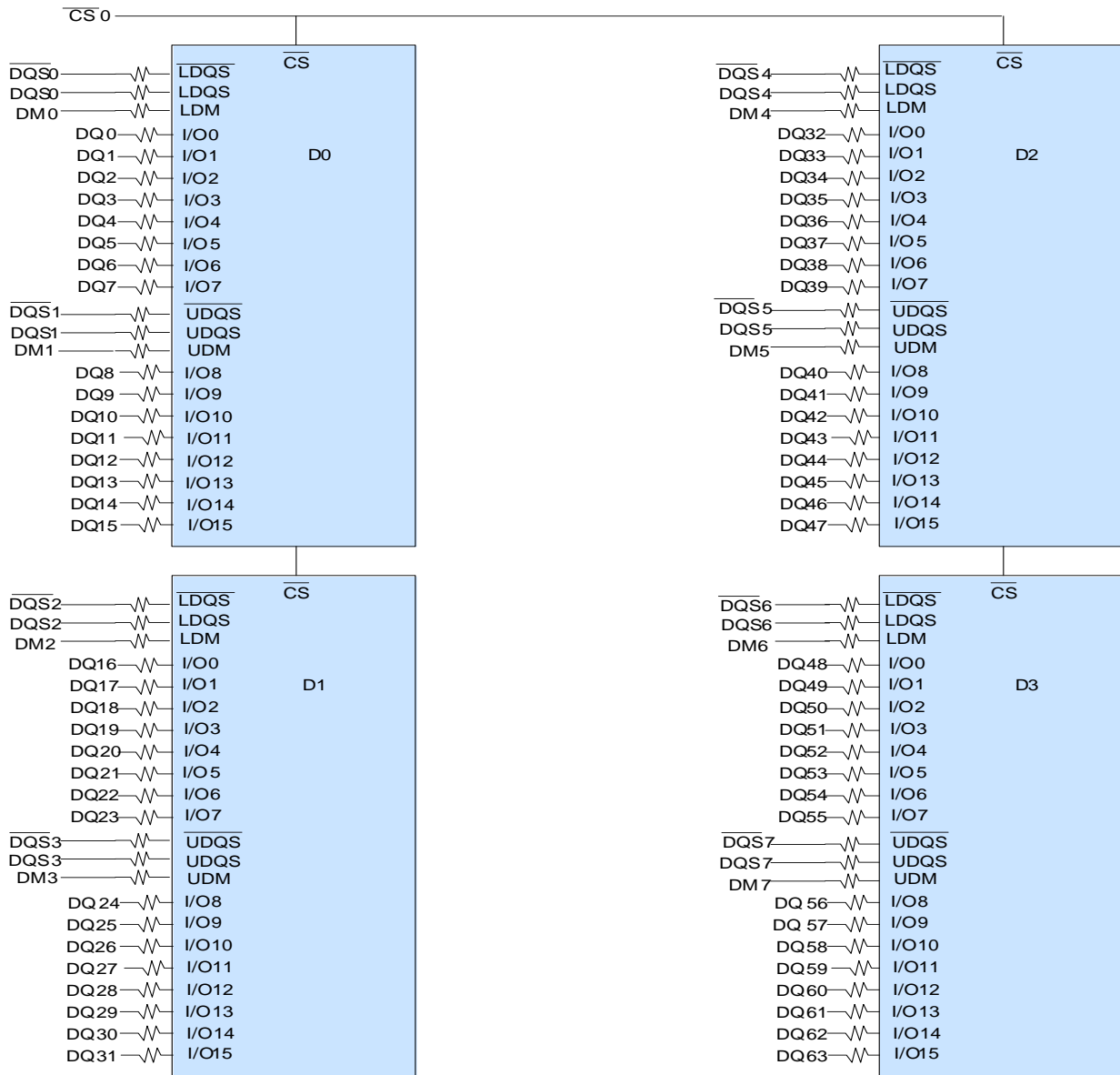
512MB: 64M x 64 / 1GB: 128M x 64 / 2GB: 256M x 64

Unbuffered DDR2 SDRAM DIMM

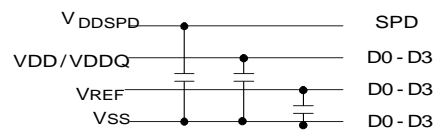
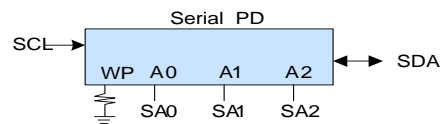


Functional Block Diagram

(512MB, 1 Rank, 64Mx16 DDR2 SDRAMs)

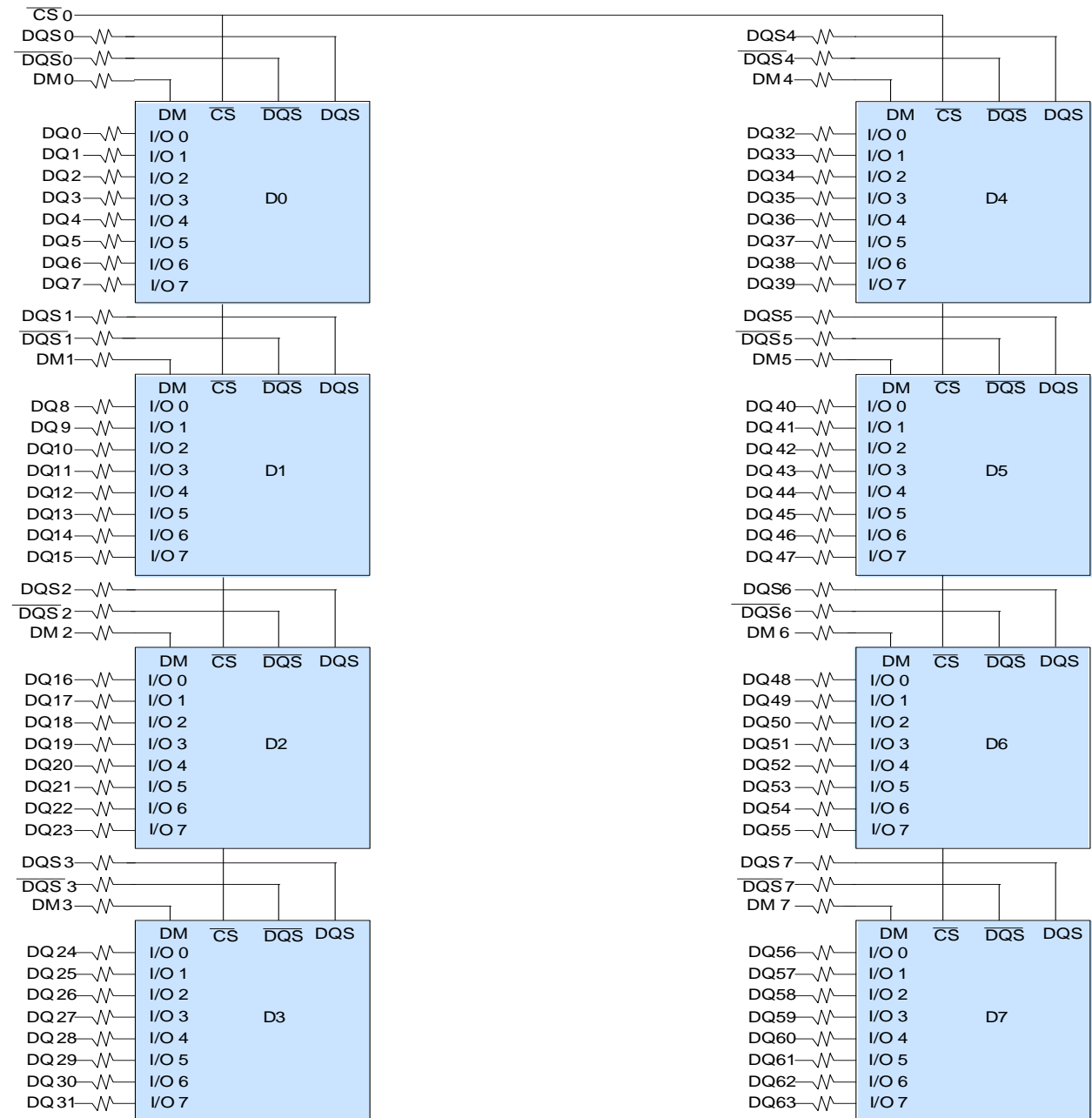


BA0-BA2 → BA0- BA2 : SDRAMs D0-D3
 A0-A12 → A0- A12 : SDRAMs D0-D3
 RAS → RAS : SDRAMs D0-D3
 CAS → CAS : SDRAMs D0-D3
 WE → WE : SDRAMs D0-D3
 CKE0 → CKE : SDRAMs D0-D3
 ODT0 → ODT : SDRAMs D0-D3

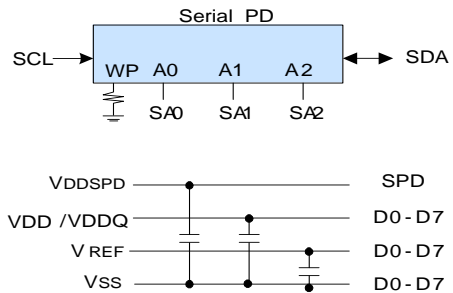


Functional Block Diagram

(1GB, 1 Rank, 128Mx8 DDR2 SDRAMs)



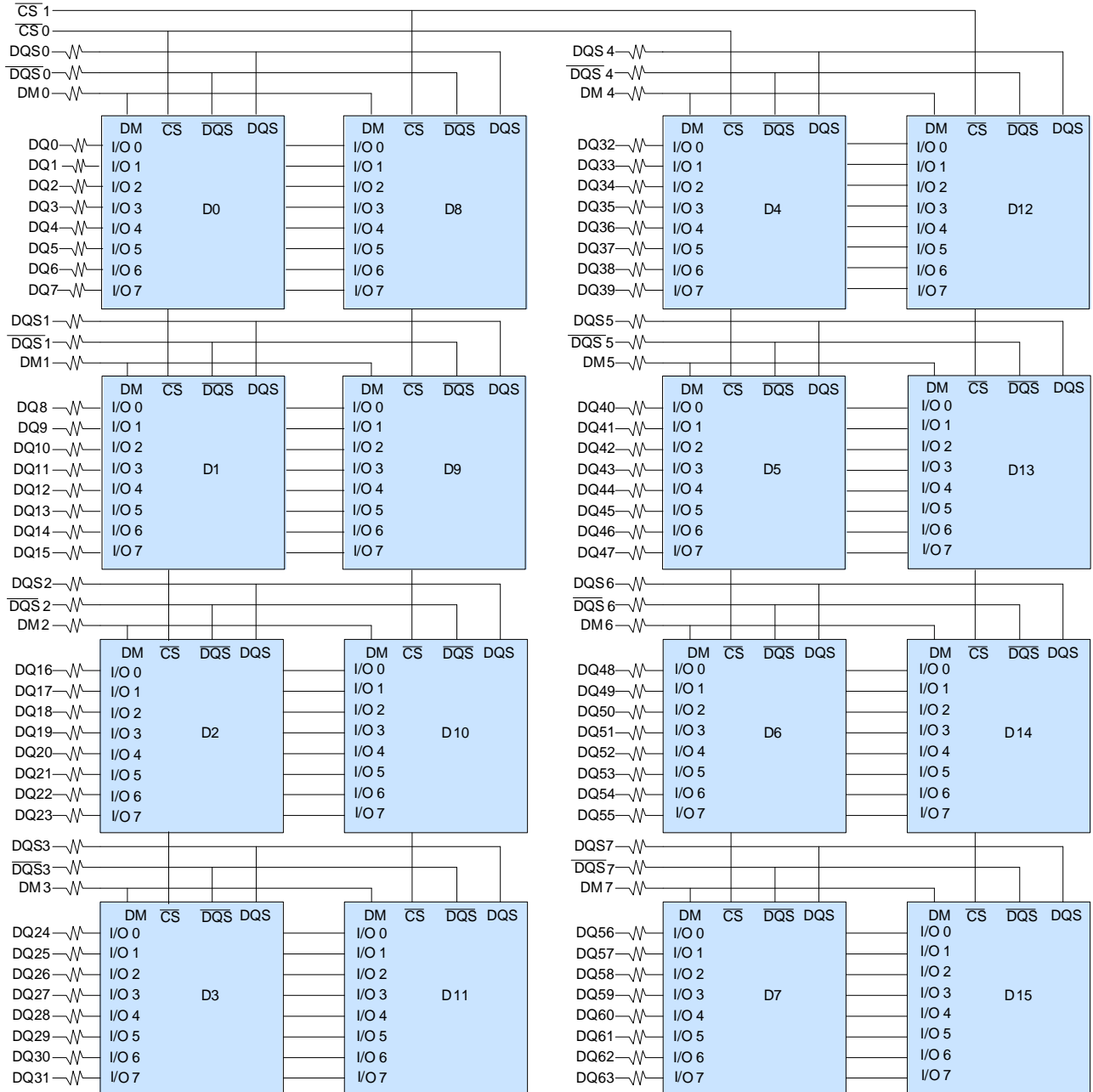
BA0-BA2 → BA0-BA2: SDRAMs D0-D7
 A0-A13 → A0-A13: SDRAMs D0-D7
 RAS → RAS: SDRAMs D0-D7
 CAS → CAS: SDRAMs D0-D7
 WE → WE: SDRAMs D0-D7
 CKE0 → CKE: SDRAMs D0-D7
 ODT0 → ODT: SDRAMs D0-D7



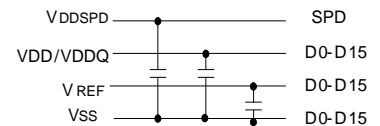
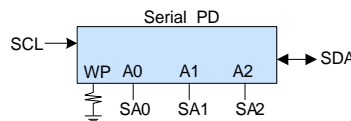


Functional Block Diagram

(2GB, 2 Ranks, 128Mx8 DDR2 SDRAMs)



- BA0-BA2 → BA0-BA2 : SDRAMs D0-D15
- A0-A13 → A0-A13 : SDRAMs D0-D15
- RAS → RAS : SDRAMs D0-D15
- CAS → CAS : SDRAMs D0-D15
- WE → WE : SDRAMs D0-D15
- CKE0 → CKE : SDRAMs D0-D7
- CKE1 → CKE : SDRAMs D8-D15
- ODT0 → ODT : SDRAMs D0-D7
- ODT1 → ODT : SDRAMs D8-D15



NT512T64UH4D0FY / NT1GT64U88D0BY / NT2GT64U8HD0BY

512MB: 64M x 64 / 1GB: 128M x 64 / 2GB: 256M x 64

Unbuffered DDR2 SDRAM DIMM



Serial Presence Detect -- Part 1 of 2 (512MB)

64Mx64 1 RANK UNBUFFERED DDR2 SDRAM DIMM based on 64Mx16, 8Banks, 8K Refresh, 1.8V DDR2 SDRAMs with SPD

Byte	Description	SPD Entry Value			Serial PD Data Entry (Hexadecimal)			Note
		667-3C	800-AD	800-AC	667-3C	800-AD	800-AC	
0	Number of Serial PD Bytes Written during Production	128			80			
1	Total Number of Bytes in Serial PD device	256			08			
2	Fundamental Memory Type	DDR2			08			
3	Number of Row Addresses on Assembly	13			0D			
4	Number of Column Addresses on Assembly	10			0A			
5	Number of DIMM Ranks	1 rank, Height=30mm			60			
6	Data Width of Assembly	X64			40			
7	Reserved	Undefined			00			
8	Voltage Interface Level of this Assembly	SSTL_1.8V			05			
9	DDR2 SDRAM Device Cycle Time at CL=5	3ns	2.5ns		30	25		
10	DDR2 SDRAM Device Access Time from Clock at CL=5	0.45ns	0.4ns		45	40		
11	DIMM Configuration Type	Non parity/ECC			00			
12	Refresh Rate/Type	7.8µs			82			
13	Primary DDR2 SDRAM Width	X16			10			
14	Error Checking DDR2 SDRAM Device Width	Undefined			00			
15	Reserved	Undefined			00			
16	DDR2 SDRAM Device Attributes: Burst Length Supported	4,8			0C			
17	DDR2 SDRAM Device Attributes: Number of Device Banks	8			08			
18	DDR2 SDRAM Device Attributes: CAS Latencies Supported	3,4,5	4,5,6	3,4,5	38	70	38	
19	DIMM Mechanical Characteristics	x ≤ 4.10 (mm)			01			
20	DDR2 SDRAM DIMM Type Information	UDIMM (133.5mm)			02			
21	DDR2 SDRAM Module Attributes:	Normal DIMM			00			
22	DDR2 SDRAM Device Attributes: General	Support weak driver, 50Ω ODT, and PASR			07			
23	Minimum Clock Cycle at CL=4	3.75ns	3.0ns	3.75ns	3D	30	3D	
24	Maximum Data Access Time from Clock at CL=4	0.5ns	0.45ns	0.5ns	50	45	50	
25	Minimum Clock Cycle Time at CL=3	5.0ns	3.75ns	5.0ns	50	3D	50	
26	Maximum Data Access Time from Clock at CL=3	0.6ns	0.5ns	0.6ns	60	50	60	
27	Minimum Row Precharge Time (t _{RP})	15ns		12.5ns	3C		32	
28	Minimum Row Active to Row Active delay (t _{RRD})	10ns			28			
29	Minimum RAS to CAS delay (t _{RCD})	15ns		12.5ns	3C		32	
30	Minimum RAS Pulse Width (t _{RAS})	45ns			2D			
31	Module Bank Density	512MB			80			
32	Address and Command Setup Time Before Clock (t _{IS})	0.20ns	0.17ns		20	17		
33	Address and Command Hold Time After Clock (t _{IH})	0.27ns	0.25ns		27	25		
34	Data Input Setup Time Before Clock (t _{DS})	0.10ns	0.05ns		10	05		
35	Data Input Hold Time After Clock (t _{DH})	0.175ns	0.12ns		17	12		
36	Write Recovery Time (t _{WR})	15.0ns			3C			
37	Internal Write to Read Command delay (t _{WTR})	7.5ns			1E			
38	Internal Read to Precharge delay (t _{RTP})	7.5ns			1E			
39	Reserved	Undefined			00			

NT512T64UH4D0FY / NT1GT64U88D0BY / NT2GT64U8HD0BY

512MB: 64M x 64 / 1GB: 128M x 64 / 2GB: 256M x 64

Unbuffered DDR2 SDRAM DIMM



Serial Presence Detect -- Part 1 of 2 (512MB)

64Mx64 1 RANK UNBUFFERED DDR2 SDRAM DIMM based on 64Mx16, 8Banks, 8K Refresh, 1.8V DDR2 SDRAMs with SPD

Byte	Description	SPD Entry Value			Serial PD Data Entry (Hexadecimal)			Note
		667-3C	800-AD	800-AC	667-3C	800-AD	800-AC	
40	Extension of Byte 41 tRC and Byte 42 tRFC	The number below a decimal point of tRC and tRFC are 0, tRFC is less than 256ns.			06		36	
41	Minimum Core Cycle Time (tRC)	60.0ns		57.5ns	3C		39	
42	Min. Auto Refresh Command Cycle Time (tRFC)	127.5ns			7F			
43	Maximum Clock Cycle Time (tCK)	8.0ns			80			
44	Max. DQS-DQ Skew Factor (tQHS)	0.24ns	0.20ns		18	14		
45	Read Data Hold Skew Factor (tQHS)	0.34ns	0.30ns		22	1E		
46	PLL Relock Time	Undefined			00			
46-61	Reserved	Undefined			00			
62	SPD Revision	1.3			13			
63	Checksum for bytes 0-62	Checksum Data			A7	71	8D	
64-71	Manufacture's JEDEC ID Code	NANYA			7F7F7F0B00000000			
72	Module Manufacturing Location	Manufacturing Code			--			
73-91	Module Part number	Module Part Number in ASCII			--			1
92-255	Reserved	Undefined			--			

Note 1:

NT512T64UH4D0FY-3C → 4E54353132543634554834443046592D334320
 NT512T64UH4D0FY-AD → 4E54353132543634554834443046592D414420
 NT512T64UH4D0FY-AC → 4E54353132543634554834443046592D414320

NT512T64UH4D0FY / NT1GT64U88D0BY / NT2GT64U8HD0BY

512MB: 64M x 64 / 1GB: 128M x 64 / 2GB: 256M x 64

Unbuffered DDR2 SDRAM DIMM



Serial Presence Detect -- Part 1 of 2 (1GB)

128Mx64 1 RANK UNBUFFERED DDR2 SDRAM DIMM based on 128Mx8, 8Banks, 8K Refresh, 1.8V DDR2 SDRAMs with SPD

Byte	Description	SPD Entry Value			Serial PD Data Entry (Hexadecimal)			Note
		667 -3C	800 -AD	800 -AC	667 -3C	800 -AD	800 -AC	
0	Number of Serial PD Bytes Written during Production	128			80			
1	Total Number of Bytes in Serial PD device	256			08			
2	Fundamental Memory Type	DDR2			08			
3	Number of Row Addresses on Assembly	14			0E			
4	Number of Column Addresses on Assembly	10			0A			
5	Number of DIMM Ranks	1 rank, Height=30mm			60			
6	Data Width of Assembly	X64			40			
7	Reserved	Undefined			00			
8	Voltage Interface Level of this Assembly	SSTL_1.8V			05			
9	DDR2 SDRAM Device Cycle Time at CL=5	3ns	2.5ns		30	25		
10	DDR2 SDRAM Device Access Time from Clock at CL=5	0.45ns	0.4ns		45	40		
11	DIMM Configuration Type	Non parity/ECC			00			
12	Refresh Rate/Type	7.8µs			82			
13	Primary DDR2 SDRAM Width	X8			08			
14	Error Checking DDR2 SDRAM Device Width	Undefined			00			
15	Reserved	Undefined			00			
16	DDR2 SDRAM Device Attributes: Burst Length Supported	4,8			0C			
17	DDR2 SDRAM Device Attributes: Number of Device Banks	8			08			
18	DDR2 SDRAM Device Attributes: CAS Latencies Supported	3,4,5	4,5,6	3,4,5	38	70	38	
19	DIMM Mechanical Characteristics	x ≤ 4.10 (mm)			01			
20	DDR2 SDRAM DIMM Type Information	UDIMM (133.5mm)			02			
21	DDR2 SDRAM Module Attributes:	Normal DIMM			00			
22	DDR2 SDRAM Device Attributes: General	Support weak driver, 50Ω ODT, and PASR			07			
23	Minimum Clock Cycle at CL=4	3.75ns	3.0ns	3.75ns	3D	30	3D	
24	Maximum Data Access Time from Clock at CL=4	0.5ns	0.45ns	0.5ns	50	45	50	
25	Minimum Clock Cycle Time at CL=3	5.0ns	3.75ns	5.0ns	50	3D	50	
26	Maximum Data Access Time from Clock at CL=3	0.6ns	0.5ns	0.6ns	60	50	60	
27	Minimum Row Precharge Time (t _{RP})	15ns		12.5ns	3C		32	
28	Minimum Row Active to Row Active delay (t _{RRD})	7.5ns			1E			
29	Minimum RAS to CAS delay (t _{RCD})	15ns		12.5ns	3C		32	
30	Minimum RAS Pulse Width (t _{RAS})	45ns			2D			
31	Module Bank Density	1GB			01			
32	Address and Command Setup Time Before Clock (t _{IS})	0.20ns	0.17ns		20	17		
33	Address and Command Hold Time After Clock (t _{IH})	0.27ns	0.25ns		27	25		
34	Data Input Setup Time Before Clock (t _{DS})	0.10ns	0.05ns		10	05		
35	Data Input Hold Time After Clock (t _{DH})	0.175ns	0.12ns		17	12		
36	Write Recovery Time (t _{WR})	15.0ns			3C			
37	Internal Write to Read Command delay (t _{WTR})	7.5ns			1E			
38	Internal Read to Precharge delay (t _{RTP})	7.5ns			1E			
39	Reserved	Undefined			00			

NT512T64UH4D0FY / NT1GT64U88D0BY / NT2GT64U8HD0BY

512MB: 64M x 64 / 1GB: 128M x 64 / 2GB: 256M x 64

Unbuffered DDR2 SDRAM DIMM



Serial Presence Detect -- Part 2 of 2 (1GB)

128Mx64 1 RANK UNBUFFERED DDR2 SDRAM DIMM based on 128Mx8, 8Banks, 8K Refresh, 1.8V DDR2 SDRAMs with SPD

Byte	Description	SPD Entry Value			Serial PD Data Entry (Hexadecimal)			Note
		667 -3C	800 -AD	800 -AC	667 -3C	800 -AD	800 -AC	
40	Extension of Byte 41 tRC and Byte 42 tRFC	The number below a decimal point of tRC and tRFC are 0, tRFC is less than 256ns.			06		36	
41	Minimum Core Cycle Time (tRC)	60.0ns		57.5ns	3C		39	
42	Min. Auto Refresh Command Cycle Time (tRFC)	127.5ns			7F			
43	Maximum Clock Cycle Time (tCK)	8.0ns			80			
44	Max. DQS-DQ Skew Factor (tQHS)	0.24ns	0.20ns		18	14		
45	Read Data Hold Skew Factor (tQHS)	0.34ns	0.30ns		22	1E		
46	PLL Relock Time	Undefined			00			
46-61	Reserved	Undefined			00			
62	SPD Revision	1.3			13			
63	Checksum for bytes 0-62	Checksum Data			17	E1	FD	
64-71	Manufacture's JEDEC ID Code	NANYA			7F7F7F0B00000000			
72	Module Manufacturing Location	Manufacturing Code			--			
73-91	Module Part number	Module Part Number in ASCII			--			1
92-255	Reserved	Undefined			--			

Note 1:

NT1GT64U88D0BY-3C → 4D325931473634545538384434422D33432020

NT1GT64U88D0BY-AD → 4D325931473634545538384434422D41442020

NT1GT64U88D0BY-AC → 4D325931473634545538384434422D41432020

NT512T64UH4D0FY / NT1GT64U88D0BY / NT2GT64U8HD0BY

512MB: 64M x 64 / 1GB: 128M x 64 / 2GB: 256M x 64

Unbuffered DDR2 SDRAM DIMM



Serial Presence Detect -- Part 1 of 2 (2GB)

256Mx64 2 RANKs UNBUFFERED DDR2 SDRAM DIMM based on 128Mx8, 8Banks, 8K Refresh, 1.8V DDR2 SDRAMs with SPD

Byte	Description	SPD Entry Value			Serial PD Data Entry (Hexadecimal)			Note
		667-3C	800-AD	800-AC	667-3C	800-AD	800-AC	
0	Number of Serial PD Bytes Written during Production	128			80			
1	Total Number of Bytes in Serial PD device	256			08			
2	Fundamental Memory Type	DDR2			08			
3	Number of Row Addresses on Assembly	14			0E			
4	Number of Column Addresses on Assembly	10			0A			
5	Number of DIMM Ranks	2 ranks, Height=30mm			61			
6	Data Width of Assembly	X64			40			
7	Reserved	Undefined			00			
8	Voltage Interface Level of this Assembly	SSTL_1.8V			05			
9	DDR2 SDRAM Device Cycle Time at CL=5	3.0ns	2.5ns		30	25		
10	DDR2 SDRAM Device Access Time from Clock at CL=5	0.45ns	0.4ns		45	40		
11	DIMM Configuration Type	Non parity/ECC			00			
12	Refresh Rate/Type	7.8µs/self			82			
13	Primary DDR2 SDRAM Width	X8			08			
14	Error Checking DDR2 SDRAM Device Width	N/A			00			
15	Reserved	Undefined			00			
16	DDR2 SDRAM Device Attributes: Burst Length Supported	4,8			0C			
17	DDR2 SDRAM Device Attributes: Number of Device Banks	8			08			
18	DDR2 SDRAM Device Attributes: CAS Latencies Supported	3,4,5	4,5,6	3,4,5	38	70	38	
19	DIMM Mechanical Characteristics	x ≤ 4.10 (mm)			01			
20	DDR2 SDRAM DIMM Type Information	UDIMM (133.5mm)			02			
21	DDR2 SDRAM Module Attributes:	Normal DIMM			00			
22	DDR2 SDRAM Device Attributes: General	Support weak driver, 50Ω ODT, and PASR			07			
23	Minimum Clock Cycle at CL=4	3.75ns	3ns	3.75ns	3D	30	3D	
24	Maximum Data Access Time from Clock at CL=4	0.5ns	0.45ns	0.5ns	50	45	50	
25	Minimum Clock Cycle Time at CL=3	5.0ns	3.75ns	5.0ns	50	3D	50	
26	Maximum Data Access Time from Clock at CL=3	0.6ns	0.5ns	0.6ns	60	50	60	
27	Minimum Row Precharge Time (t _{RP})	15ns		12.5ns	3C		32	
28	Minimum Row Active to Row Active delay (t _{RRD})	7.5ns			1E			
29	Minimum RAS to CAS delay (t _{RCD})	15ns		12.5ns	3C		32	
30	Minimum RAS Pulse Width (t _{RAS})	45.0			2D			
31	Module Bank Density	1GB			01			
32	Address and Command Setup Time Before Clock (t _{IS})	0.20ns	0.17ns		20	17		
33	Address and Command Hold Time After Clock (t _{IH})	0.27ns	0.25ns		27	25		
34	Data Input Setup Time Before Clock (t _{DS})	0.10ns	0.05ns		10	05		
35	Data Input Hold Time After Clock (t _{DH})	0.17ns	0.12ns		17	12		
36	Write Recovery Time (t _{WR})	15.0ns			3C			
37	Internal Write to Read Command delay (t _{WTR})	7.5ns			1E			
38	Internal Read to Precharge delay (t _{RTP})	7.5ns			1E			
39	Reserved	Undefined			00			

NT512T64UH4D0FY / NT1GT64U88D0BY / NT2GT64U8HD0BY

512MB: 64M x 64 / 1GB: 128M x 64 / 2GB: 256M x 64

Unbuffered DDR2 SDRAM DIMM



Serial Presence Detect -- Part 2 of 2 (2GB)

256Mx64 2 RANKs UNBUFFERED DDR2 SDRAM DIMM based on 128Mx8, 8Banks, 8K Refresh, 1.8V DDR2 SDRAMs with SPD

Byte	Description	SPD Entry Value			Serial PD Data Entry (Hexadecimal)			Note
		667-3C	800-AD	800-AC	667-3C	800-AD	800-AC	
40	Extension of Byte 41 tRC and Byte 42 tRFC	The number below a decimal point of tRC and tRFC are 0, tRFC is less than 256ns.			06		36	
41	Minimum Core Cycle Time (tRC)	60.0ns		57.5ns	3C		39	
42	Min. Auto Refresh Command Cycle Time (tRFC)	127.5ns			7F			
43	Maximum Clock Cycle Time (tCK)	8.0ns			80			
44	Max. DQS-DQ Skew Factor (tQHS)	0.24ns	0.20ns		18	14		
45	Read Data Hold Skew Factor (tQHS)	0.34ns	0.30ns		22	1E		
46	PLL Relock Time	Undefined			00			
46-61	Reserved	Undefined			00			
62	SPD Revision	1.3			13			
63	Checksum for bytes 0-62	Checksum Data			18	E2	FE	
64-71	Manufacture's JEDEC ID Code	NANYA			7F7F7F0B00000000			
72	Module Manufacturing Location	Manufacturing Code			--			
73-91	Module Part number	Module Part Number in ASCII			--			1
92-255	Reserved	Undefined			--			

Note 1:
 NT2GT64U8HD0BY-3C → 4D325932473634545538484434422D33432020
 NT2GT64U8HD0BY-AD → 4D325932473634545538484434422D41442020
 NT2GT64U8HD0BY-AC → 4D325932473634545538484434422D41432020



Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V_{IN}, V_{OUT}	Voltage on any pin relative to Vss	-0.5 to 2.3	V
V_{DDQ}	Voltage on V_{DDQ} supply relative to Vss	-0.5 to 2.3	V
V_{DDQL}	Voltage on V_{DDQL} supply relative to Vss	-0.5 to 2.3	V
V_{DD}	Voltage on VDD supply relative to Vss	-1.0 to +2.3	V

Note: Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is stress rating only, and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

DC Operating Conditions

Symbol	Parameter	Rating	Units	Note
T_{CASE}	Operating Temperature (Ambient)	0 to 95	°C	1,2,3
T_{STG}	Storage Temperature (Plastic)	-55 to 100	°C	
I_L	Short Circuit Output Current	-5 to 5	µA	

Note:

1. Case temperature is measured at top and center side of any DRAMs.
2. $t_{CASE} > 85^{\circ}C \rightarrow t_{REFI} = 3.9 \mu s$
3. All DRAM specification only support $0^{\circ}C < t_{CASE} < 85^{\circ}C$



DC Electrical Characteristics and Operating Conditions

(T_{CASE} = 0 °C ~ 85 °C; V_{DDQ} = 1.8V ± 0.1V; V_{DD} = 1.8V ± 0.1V, See AC Characteristics)

Symbol	Parameter	Min	Max	Units	Notes
V _{DD}	Supply Voltage	1.7	1.9	V	1
V _{DDQ}	Supply Voltage for Output	1.7	1.9	V	1, 3
V _{DDL}	Supply Voltage for V _{DDL}	1.7	1.9	V	3
V _{REF}	Input Reference Voltage	0.49V _{DDQ}	0.51V _{DDQ}	mV	2
V _{TT}	Termination Voltage	V _{REF} - 0.04	V _{REF} + 0.04	V	4
V _{IH} (DC)	Input High (Logic1) Voltage	V _{REF} + 0.125	V _{DDQ} + 0.3	V	
V _{IL} (DC)	Input Low (Logic0) Voltage	-0.3	V _{REF} - 0.125	V	

Note:

- Inputs are not recognized as valid until V_{REF} stabilizes.
- V_{REF} is expected to be equal to 0.5 V DDQ of the transmitting device, and to track variations in the DC level of the same. Peak-to-peak noise on V_{REF} may not exceed 2% of the DC value.
- V_{DDQ} tracks with V_{DD}, V_{DDL} tracks with V_{DD}.
- V_{TT} of transmitting device track V_{REF} of receiving device.

Environmental Parameters

Symbol	Parameter	Rating	Units	Note
T _{OPR}	Module Operating Temperature Range (ambient)	0 to 55	°C	3
H _{OPR}	Operating Humidity (relative)	10 to 90	%	
T _{STG}	Storage Temperature (Plastic)	-55 to 100	°C	1
H _{STG}	Storage Humidity (without condensation)	5 to 95	%	1
P _{BAR}	Barometric Pressure (operating & storage)	105 to 69	K Pascal	1,2

Note:

- Stresses greater than those listed may cause permanent damage to the device. This is a stress rating only, and device functional operation at or above the conditions indicated is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
- Up to 9850 ft.
- The component maximum case temperature shall not exceed the value specified in the component spec.



Operating, Standby, and Refresh Currents

T_{CASE} = 0 °C ~ 85 °C; V_{DDQ} = V_{DD} = 1.8V ± 0.1V (512MB, 1 Rank, 64Mx16 DDR2 SDRAMs)

Symbol	Parameter/Condition	PC2-5300 (-3C)	PC2-6400 (-AD)	PC2-6400 (-AC)	Unit
I _{DD0}	Operating Current: one bank; active/precharge; t _{RC} = t _{RC} (MIN); t _{CK} = t _{CK} (MIN); DQ, DM, and DQS inputs changing twice per clock cycle; address and control inputs changing once per clock cycle	436	502	502	mA
I _{DD1}	Operating Current: one bank; active/read/precharge; Burst = 2; t _{RC} = t _{RC} (MIN); CL=2.5; t _{CK} = t _{CK} (MIN); I _{OUT} = 0mA; address and control inputs changing once per clock cycle	541	620	620	mA
I _{DD2P}	Precharge Power-Down Standby Current: all banks idle; power-down mode; CKE ≤ V _{IL} (MAX); t _{CK} = t _{CK} (MIN)	35	35	35	mA
I _{DD2N}	Idle Standby Current: CS ≥ V _{IH} (MIN); all banks idle; CKE ≥ V _{IH} (MIN); t _{CK} = t _{CK} (MIN); address and control inputs changing once per clock cycle	273	308	308	mA
I _{DD2Q}	Precharge Quiet Standby Current: All banks idle; \overline{CS} is HIGH; CKE is HIGH; t _{CK} = t _{CK} (MIN); Other control and address inputs are stable, Data bus inputs are floating.	189	207	207	mA
I _{DD3PF}	Active Power-Down Current: All banks open; t _{CK} = t _{CK} (MIN), CKE is LOW; Other control and address inputs are STABLE, Data bus inputs are floating. MRS A12 bit is set to low (Fast Power-down Exit).	123	132	132	mA
I _{DD3PS}	Active Power-Down Current: All banks open; t _{CK} = t _{CK} (MIN), CKE is LOW; Other control and address inputs are STABLE, Data bus inputs are floating. MRS A12 bit is set to high (Slow Power-down Exit).	53	53	53	mA
I _{DD3N}	Active Standby Current: one bank; active/precharge; CS ≥ V _{IH} (MIN); CKE ≥ V _{IH} (MIN); t _{RC} = t _{RAS} (MAX); t _{CK} = t _{CK} (MIN); DQ, DM, and DQS inputs changing twice per clock cycle; address and control inputs changing once per clock cycle	255	282	282	mA
I _{DD4W}	Operating Current: one bank; Burst = 2; writes; continuous burst; address and control inputs changing once per clock cycle; DQ and DQS inputs changing twice per clock cycle; CL=2.5; t _{CK} = t _{CK} (MIN)	550	607	607	mA
I _{DD4R}	Operating Current: one bank; Burst = 2; reads; continuous burst; address and control inputs changing once per clock cycle; DQ and DQS outputs changing twice per clock cycle; CL = 2.5; t _{CK} = t _{CK} (MIN); I _{OUT} = 0mA	673	752	752	mA
I _{DD5}	Auto-Refresh Current: t _{RC} = t _{RFC} (MIN)	968	990	990	mA
I _{DD6}	Self-Refresh Current: CKE ≤ 0.2V	40	40	40	mA
I _{DD7}	Operating Current: four bank; four bank interleaving with BL = 4, address and control inputs randomly changing; 50% of data changing at every transfer; t _{RC} = t _{RC} (min); I _{OUT} = 0mA.	1496	1672	1672	mA
Note: Module IDD was calculated from component IDD. It may differ from the actual measurement.					



Operating, Standby, and Refresh Currents

T_{CASE} = 0 °C ~ 85 °C; V_{DDQ} = V_{DD} = 1.8V ± 0.1V (1GB, 1 Rank, 128Mx8 DDR2 SDRAMs)

Symbol	Parameter/Condition	PC2-5300 (-3C)	PC2-6400 (-AD)	PC2-6400 (-AC)	Unit
I _{DD0}	Operating Current: one bank; active/precharge; t _{RC} = t _{RC} (MIN); t _{CK} = t _{CK} (MIN); DQ, DM, and DQS inputs changing twice per clock cycle; address and control inputs changing once per clock cycle	880	1012	1012	mA
I _{DD1}	Operating Current: one bank; active/read/precharge; Burst = 2; t _{RC} = t _{RC} (MIN); CL=2.5; t _{CK} = t _{CK} (MIN); I _{OUT} = 0mA; address and control inputs changing once per clock cycle	801	906	906	mA
I _{DD2P}	Precharge Power-Down Standby Current: all banks idle; power-down mode; CKE ≤ V _{IL} (MAX); t _{CK} = t _{CK} (MIN)	70	70	70	mA
I _{DD2N}	Idle Standby Current: CS ≥ V _{IH} (MIN); all banks idle; CKE ≥ V _{IH} (MIN); t _{CK} = t _{CK} (MIN); address and control inputs changing once per clock cycle	554	625	625	mA
I _{DD2Q}	Precharge Quiet Standby Current: All banks idle; \overline{CS} is HIGH; CKE is HIGH; t _{CK} = t _{CK} (MIN); Other control and address inputs are stable, Data bus inputs are floating.	387	422	422	mA
I _{DD3PF}	Active Power-Down Current: All banks open; t _{CK} = t _{CK} (MIN), CKE is LOW; Other control and address inputs are STABLE, Data bus inputs are floating. MRS A12 bit is set to low (Fast Power-down Exit).	264	273	273	mA
I _{DD3PS}	Active Power-Down Current: All banks open; t _{CK} = t _{CK} (MIN), CKE is LOW; Other control and address inputs are STABLE, Data bus inputs are floating. MRS A12 bit is set to high (Slow Power-down Exit).	114	114	114	mA
I _{DD3N}	Active Standby Current: one bank; active/precharge; CS ≥ V _{IH} (MIN); CKE ≥ V _{IH} (MIN); t _{RC} = t _{RAS} (MAX); t _{CK} = t _{CK} (MIN); DQ, DM, and DQS inputs changing twice per clock cycle; address and control inputs changing once per clock cycle	493	537	537	mA
I _{DD4W}	Operating Current: one bank; Burst = 2; writes; continuous burst; address and control inputs changing once per clock cycle; DQ and DQS inputs changing twice per clock cycle; CL=2.5; t _{CK} = t _{CK} (MIN)	924	1012	1012	mA
I _{DD4R}	Operating Current: one bank; Burst = 2; reads; continuous burst; address and control inputs changing once per clock cycle; DQ and DQS outputs changing twice per clock cycle; CL = 2.5; t _{CK} = t _{CK} (MIN); I _{OUT} = 0mA	1074	1197	1197	mA
I _{DD5}	Auto-Refresh Current: t _{RC} = t _{RFC} (MIN)	1936	1980	1980	mA
I _{DD6}	Self-Refresh Current: CKE ≤ 0.2V	79	79	79	mA
I _{DD7}	Operating Current: four bank; four bank interleaving with BL = 4, address and control inputs randomly changing; 50% of data changing at every transfer; t _{RC} = t _{RC} (min); I _{OUT} = 0mA.	2094	2446	2446	mA
Note: Module IDD was calculated from component IDD. It may differ from the actual measurement.					



Operating, Standby, and Refresh Currents

T_{CASE} = 0 °C ~ 85 °C; V_{DDQ} = V_{DD} = 1.8V ± 0.1V (2GB, 2 Ranks, 128Mx8 DDR2 SDRAMs)

Symbol	Parameter/Condition	PC2-5300 (-3C)	PC2-6400 (-AD)	PC2-6400 (-AC)	Unit
I _{DD0}	Operating Current: one bank; active/precharge; t _{RC} = t _{RC} (MIN); t _{CK} = t _{CK} (MIN); DQ, DM, and DQS inputs changing twice per clock cycle; address and control inputs changing once per clock cycle	1373	1549	1549	mA
I _{DD1}	Operating Current: one bank; active/read/precharge; Burst = 2; t _{RC} = t _{RC} (MIN); CL=2.5; t _{CK} = t _{CK} (MIN); I _{OUT} = 0mA; address and control inputs changing once per clock cycle	1294	1443	1443	mA
I _{DD2P}	Precharge Power-Down Standby Current: all banks idle; power-down mode; CKE ≤ V _{IL} (MAX); t _{CK} = t _{CK} (MIN)	141	141	141	mA
I _{DD2N}	Idle Standby Current: CS ≥ V _{IH} (MIN); all banks idle; CKE ≥ V _{IH} (MIN); t _{CK} = t _{CK} (MIN); address and control inputs changing once per clock cycle	1109	1250	1250	mA
I _{DD2Q}	Precharge Quiet Standby Current: All banks idle; \overline{CS} is HIGH; CKE is HIGH; t _{CK} = t _{CK} (MIN); Other control and address inputs are stable, Data bus inputs are floating.	774	845	845	mA
I _{DD3PF}	Active Power-Down Current: All banks open; t _{CK} = t _{CK} (MIN), CKE is LOW; Other control and address inputs are STABLE, Data bus inputs are floating. MRS A12 bit is set to low (Fast Power-down Exit).	528	546	546	mA
I _{DD3PS}	Active Power-Down Current: All banks open; t _{CK} = t _{CK} (MIN), CKE is LOW; Other control and address inputs are STABLE, Data bus inputs are floating. MRS A12 bit is set to high (Slow Power-down Exit).	229	229	229	mA
I _{DD3N}	Active Standby Current: one bank; active/precharge; CS ≥ V _{IH} (MIN); CKE ≥ V _{IH} (MIN); t _{RC} = t _{RAS} (MAX); t _{CK} = t _{CK} (MIN); DQ, DM, and DQS inputs changing twice per clock cycle; address and control inputs changing once per clock cycle	986	1074	1074	mA
I _{DD4W}	Operating Current: one bank; Burst = 2; writes; continuous burst; address and control inputs changing once per clock cycle; DQ and DQS inputs changing twice per clock cycle; CL=2.5; t _{CK} = t _{CK} (MIN)	1417	1549	1549	mA
I _{DD4R}	Operating Current: one bank; Burst = 2; reads; continuous burst; address and control inputs changing once per clock cycle; DQ and DQS outputs changing twice per clock cycle; CL = 2.5; t _{CK} = t _{CK} (MIN); I _{OUT} = 0mA	1566	1734	1734	mA
I _{DD5}	Auto-Refresh Current: t _{RC} = t _{RFC} (MIN)	2429	2517	2517	mA
I _{DD6}	Self-Refresh Current: CKE ≤ 0.2V	158	158	158	mA
I _{DD7}	Operating Current: four bank; four bank interleaving with BL = 4, address and control inputs randomly changing; 50% of data changing at every transfer; t _{RC} = t _{RC} (min); I _{OUT} = 0mA.	2587	2983	2983	mA
Note: Module IDD was calculated from component IDD. It may differ from the actual measurement.					



AC Timing Specifications for DDR2 SDRAM Devices Used on Module

(T_{CASE} = 0 °C ~ 85 °C; V_{DDQ} = 1.8V ± 0.1V; V_{DD} = 1.8V ± 0.1V, See AC Characteristics) (Part 1 of 2)

Symbol	Parameter	PC2-5300		PC2-6400		Unit
		Min.	Max.	Min.	Max.	
tCK	Clock Cycle Time (Average)	3000	8000	2500	8000	ps
tCH	CK high-level width (Average)	0.48	0.52	0.48	0.52	tCK
tCL	CK low-level width (Average)	0.48	0.52	0.48	0.52	tCK
WL	Write command to DQS associated clock edge	RL-1		RL-1		nCK
tdQSS	Write command to 1st DQS latching transition	-0.25	0.25	-0.25	0.25	tCK
tdSS	DQS falling edge to CK setup time (write cycle)	0.2	-	0.2	-	tCK
tDSH	DQS falling edge hold time from CK (write cycle)	0.2	-	0.2	-	tCK
tdQSL(H)	DQS input low (high) pulse width (write cycle)	0.35	-	0.35	-	tCK
tWPRE	Write preamble	0.35	-	0.35	-	tCK
tWPST	Write postamble	0.4	0.6	0.4	0.6	tCK
tIS	Address and control input setup time	200	-	175	-	ps
tIH	Address and control input hold time	275	-	250	-	ps
tIPW	Input pulse width	0.6	-	0.6	-	tCK
tDS	DQ and DM input setup time(differential data strobe)	100	-	50	-	ps
tDH	DQ and DM input hold time(differential data strobe)	175	-	125	-	ps
tdIPW	DQ and DM input pulse width (each input)	0.35	-	0.35	-	tCK
tAC	DQ output access time from CK/ \overline{CK}	-450	450	-400	400	ps
tdQSCK	DQS output access time from CK/ \overline{CK}	-400	400	-350	350	ps
tHZ	Data-out high-impedance time from CK/ \overline{CK}	-	t _{AC} max	-	t _{AC} max	ps
tLZ(DQS)	DQS low-impedance time from CK/ \overline{CK}	t _{AC} min	t _{AC} max	t _{AC} min	t _{AC} max	ps
tLZ(DQ)	DQ low-impedance time from CK/ \overline{CK}	2t _{AC} min	t _{AC} max	2t _{AC} min	t _{AC} max	ps
tdQSQ	DQS-DQ skew (DQS & associated DQ signals)	-	240	-	200	ps
tHP	Minimum half clk period for any given cycle; defined by clk high (tCH) or clk low (tCL) time	Min(tCH(abs), tCL(abs))	-	Min(tCH(abs), tCL(abs))	-	ps
tQHS	Data hold Skew Factor	-	340	-	300	ps
tQH	Data output hold time from DQS	t _{HP} - t _{QHS}	-	t _{HP} - t _{QHS}	-	ps
tRPRE	Read preamble	0.9	1.1	0.9	1.1	tCK
tRPST	Read postamble	0.4	0.6	0.4	0.6	tCK
tRRD	Active bank A to Active bank B command	7.5	-	7.5	-	ns
tFAW	Four Activate Window for 1KB page size products	37.5	-	35	-	ns
tCCD	CAS to CAS	2	-	2	-	nCK
tWR	Write recovery time without Auto-Precharge	15	-	15	-	ns
tdAL	Auto precharge write recovery + precharge time	WR+t _{nRP}	-	WR+t _{nRP}	-	nCK
tWTR	Internal write to read command delay	7.5	-	7.5	-	ns
tRTP	Internal read to precharge command delay	7.5	-	7.5	-	ns
tCKE	CKE minimum pulse width	3	-	3	-	nCK
tXSNR	Exit self refresh to a Non-read command	t _{RFC} +10	-	t _{RFC} +10	-	ns
tXSRD	Exit self refresh to a Read command	200	-	200	-	nCK
tXP	Exit precharge power down to any Non- read command	2	-	2	-	nCK

AC Timing Specifications for DDR2 SDRAM Devices Used on Module

(T_{CASE} = 0 °C ~ 85 °C; V_{DDQ} = 1.8V ± 0.1V; V_{DD} = 1.8V ± 0.1V, See AC Characteristics) (Part 2 of 2)

Symbol	Parameter	PC2-5300		PC2-6400		Unit
		Min.	Max.	Min.	Max.	
tXARD	Exit active power down to read command	2	-	2	-	nCK
tXARSD	Exit active power down to read command	7-AL		8-AL		nCK
tAOND	ODT turn-on delay	2	2	2	2	nCK
tAON	ODT turn-on	tAC (min)	tAC (max)+0.7	tAC (min)	tAC (max)+0.7	ns
tAONPD	ODT turn-on (Power down mode)	tAC (min) +2	2tCK + tAC(max) +1	tAC (min) +2	2tCK + tAC(max) +1	ns
tAOFD	ODT turn-off delay	2.5	2.5	2.5	2.5	nCK
tAOF	ODT turn-off	tAC(min)	tAC(max) +0.6	tAC(min)	tAC(max) +0.6	ns
tAOFPD	ODT turn-off (Power down mode)	tAC (min)+2	2.5tCK + tAC(max) +1	tAC (min)+2	2.5tCK + tAC(max) +1	ns
tANPD	ODT to power down entry latency	3	-	3	-	nCK
tAXPD	ODT power down exit latency	8		8		nCK
tMRD	Mode register set command cycle time	2	-	2	-	nCK
tMOD	MRS command to ODT update delay	0	12	0	12	ns
tOIT	OCD drive mode output delay	0	12	0	12	ns
tDelay	Minimum time clocks remains ON after CKE asynchronously drops Low	tIS + tCK + tIH	-	tIS + tCK + tIH	-	ns
tRFC	Refresh to active/Refresh command time	127.5		127.5		ns
tREFI	Average Periodic Refresh Interval (85°C < T _{CASE} ≤ 95°C)	3.9		3.9		µs
	Average Periodic Refresh Interval (0°C ≤ T _{CASE} ≤ 85°C)	7.8		7.8		µs

Speed Grade Definition

Symbol	Parameter	-3C		-AD		-AC		Unit
		Min	Max	Min	Max	Min	Max	
tRAS	Row Active Time	45	70,000	45	70,000	45	70,000	ns
tRC	Row Cycle Time	60	-	60	-	57.5	-	ns
tRCD	RAS to CAS delay	15	-	15	-	12.5	-	ns
tRP	Row Precharge Time	15	-	15	-	12.5	-	ns

NT512T64UH4D0FY / NT1GT64U88D0BY / NT2GT64U8HD0BY

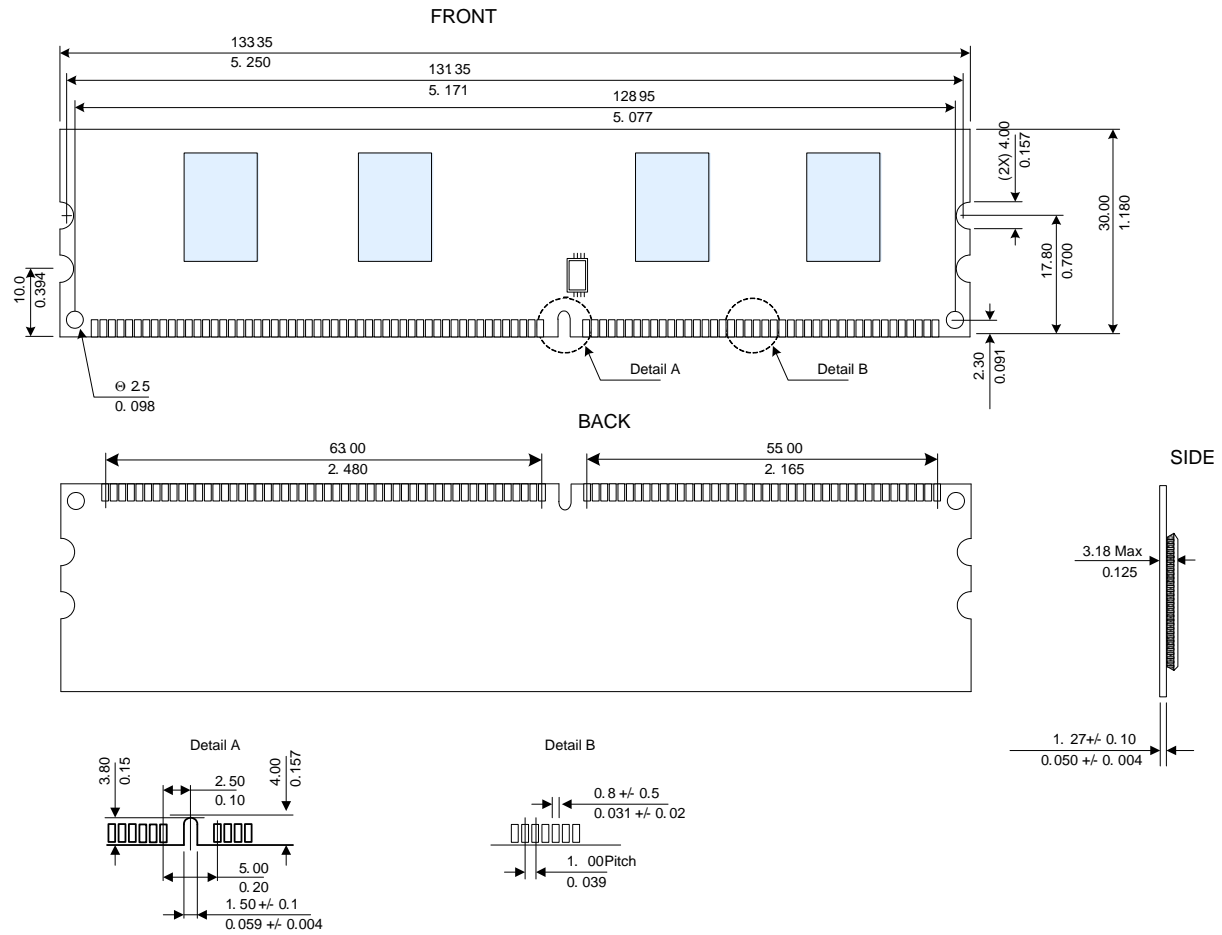
512MB: 64M x 64 / 1GB: 128M x 64 / 2GB: 256M x 64

Unbuffered DDR2 SDRAM DIMM



Package Dimensions

(Raw Card Version: C, 512MB, 1 Rank, 64Mx16 DDR2 SDRAMs)

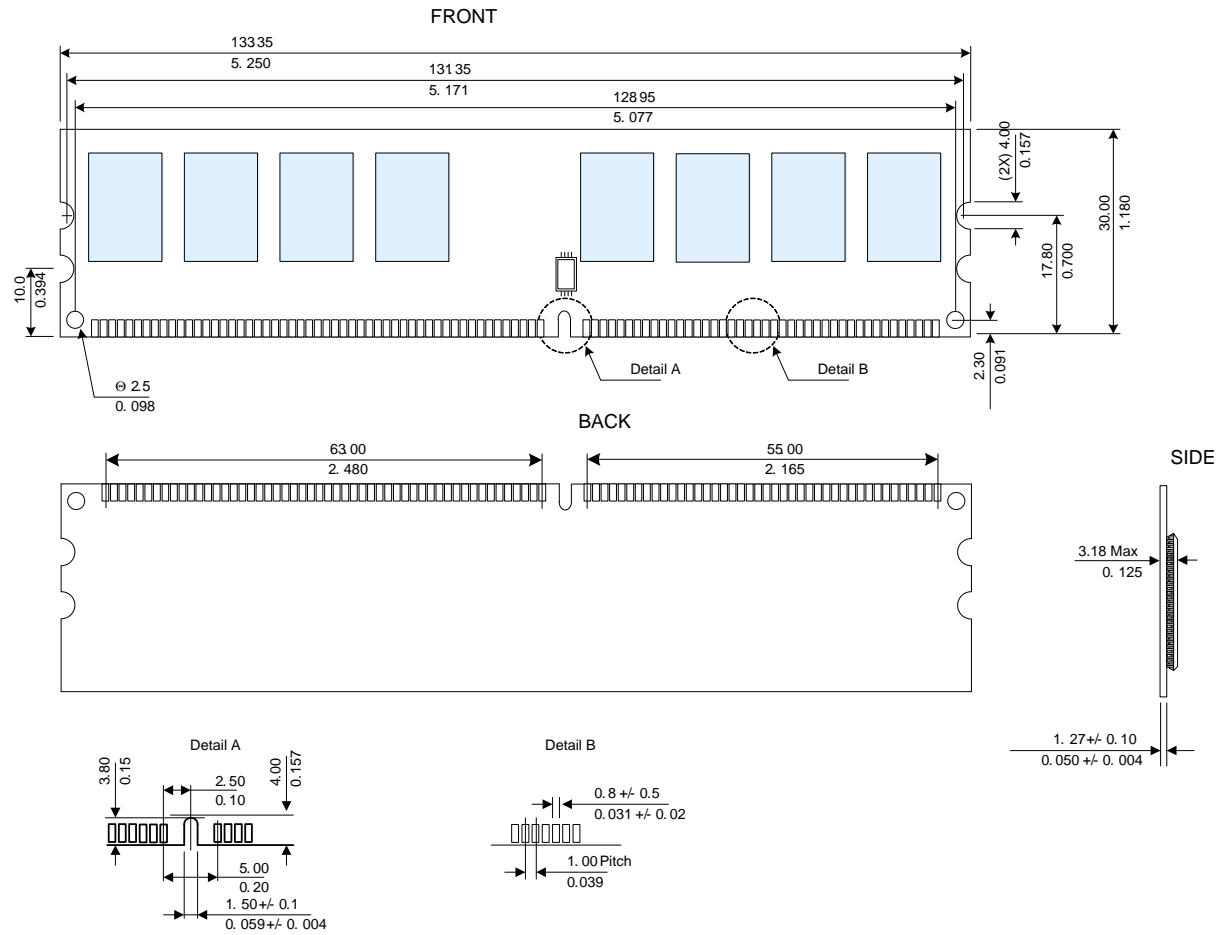


Note: All dimensions are typical with tolerances of +/- 0.15 (0.006) unless otherwise stated

Units: Millimeters (Inches)

Package Dimensions

(Raw Card Version: D, 1GB, 1 Rank, 128Mx8 DDR2 SDRAMs)



Note: All dimensions are typical with tolerances of +/- 0.15(0.006) unless otherwise stated

Units: Millimeters (Inches)

NT512T64UH4D0FY / NT1GT64U88D0BY / NT2GT64U8HD0BY

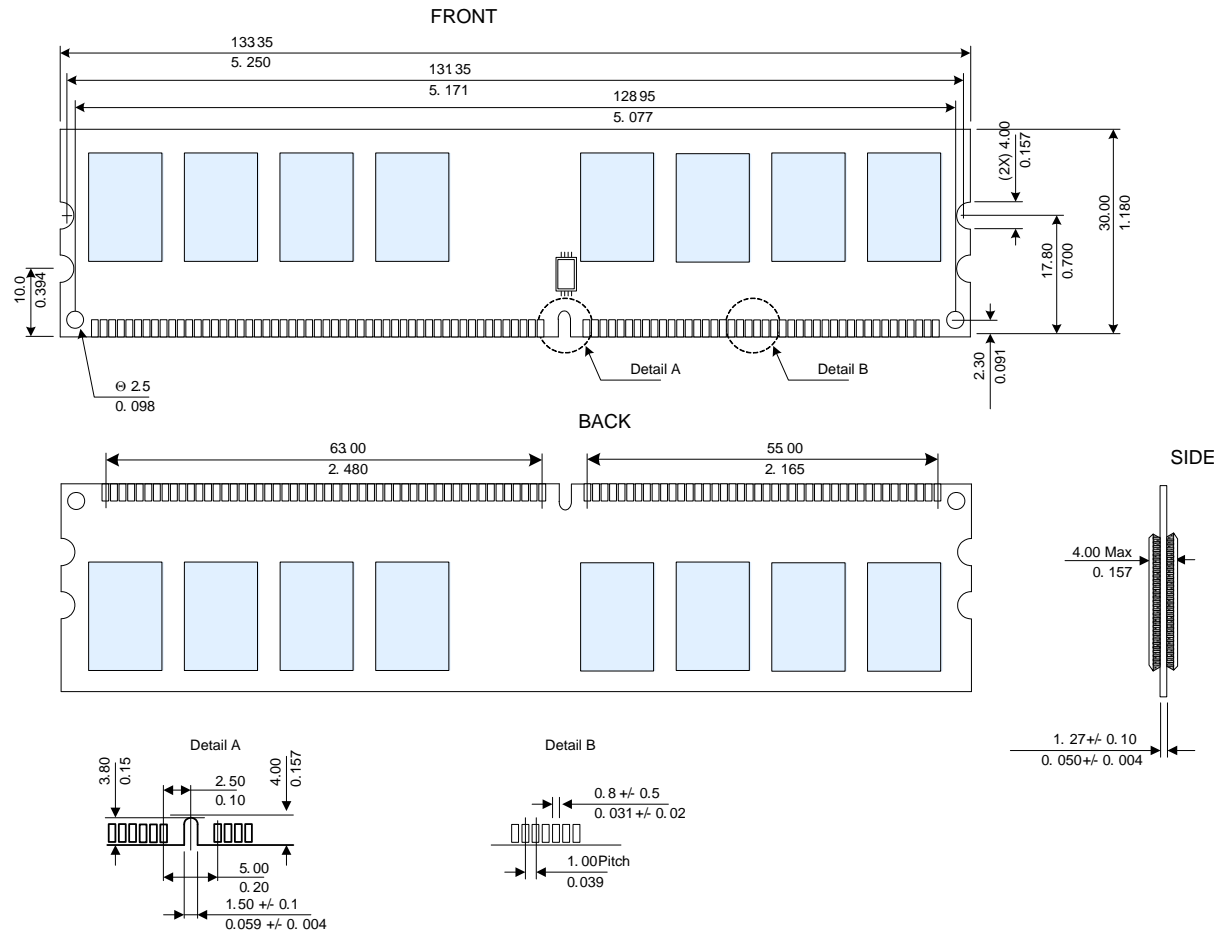
512MB: 64M x 64 / 1GB: 128M x 64 / 2GB: 256M x 64

Unbuffered DDR2 SDRAM DIMM



Package Dimensions

(Raw Card Version: E, 2GB, 2 Ranks, 128Mx8 DDR2 SDRAMs)



Note: All dimensions are typical with tolerances of +/- 0.15 (0.006) unless otherwise stated

Units: Millimeters (Inches)

NT512T64UH4D0FY / NT1GT64U88D0BY / NT2GT64U8HD0BY

512MB: 64M x 64 / 1GB: 128M x 64 / 2GB: 256M x 64

Unbuffered DDR2 SDRAM DIMM



Revision Log

Rev	Date	Modification
0.1	02/2008	Preliminary Edition
1.0	03/2008	Official Release